Product data sheet

1. General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

2. Features and benefits

- AEC Q101 compliant
- Electrostatically robust due to integrated protection diodes
- Low conduction losses due to low on-state resistance

3. Applications

Automotive and general purpose power switching

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C		-	-	55	V
I _D	drain current	T _{sp} = 25 °C		-	-	7.5	Α
P _{tot}	total power dissipation	T _{sp} = 25 °C; <u>Fig. 4</u>		-	-	8.3	W
Static characte	eristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 5 \text{ A}; T_j = 25 \text{ °C}$		-	65	80	mΩ
Avalanche rug	Avalanche ruggedness						
E _{DS(AL)S}	non-repetitive drain- source avalanche energy	I_D = 2.5 A; $V_{sup} \le$ 25 V; R_{GS} = 50 Ω; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	-	30	mJ





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5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	4	D I
2	D	drain		
3	S	source		G + T
4	D	mounting base; connected to drain	⊟1 ⊟2 ⊟3 SC-73 (SOT223)	S sym116

6. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK7880-55	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223
BUK7880-55/CU	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223

7. Marking

Table 4. Marking codes

Type number	Marking code
BUK7880-55	
BUK7880-55/CU	xxYWW 78055

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	55	V
V_{DGR}	drain-gate voltage	R_{GS} = 20 k Ω	-	55	V
V_{GS}	gate-source voltage		-16	16	V
P _{tot}	total power dissipation	T _{sp} = 25 °C; <u>Fig. 4</u>	-	8.3	W
I _D	drain current	T _{sp} = 25 °C	-	7.5	Α
		T _{sp} = 100 °C	-	4.7	Α

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Symbol	Parameter	Conditions		Min	Max	Unit
I _{DM}	peak drain current	T _{sp} = 25 °C; pulsed		-	40	Α
T _{stg}	storage temperature			-55	150	°C
T _j	junction temperature			-55	150	°C
Source-drain	diode		'			
I _S	source current	T _{sp} = 25 °C		-	7.5	Α
I _{SM}	peak source current	pulsed; T _{sp} = 25 °C		-	40	Α
Avalanche ru	ggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	I_D = 2.5 A; V_{sup} ≤ 25 V; R_{GS} = 50 Ω ; V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; unclamped		-	30	mJ
Electrostatic	discharge					
V _{esd}	electrostatic discharge voltage	HBM; C = 100 pF; R = 1.5 kΩ		-	2	kV

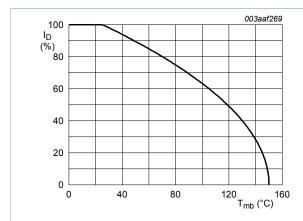
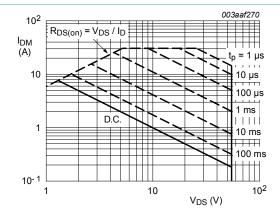


Fig. 1. Normalized continuous drain current as a function of solder point temperature

$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100 \%$$



 T_{sp} = 25 °C; I_{DM} is single pulse

Fig. 2. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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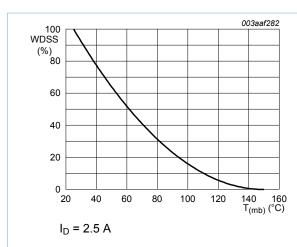


Fig. 3. Normalised drain-source non-repetitive avalanche energy as a function of mountingbase temperature

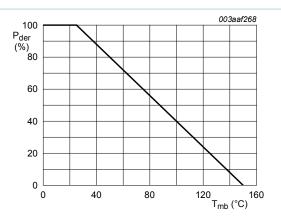


Fig. 4. Normalized total power dissipation as a function of solder point temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-sp)}	thermal resistance from junction to solder point	mounted on any printed-circuit board	-	12	15	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	Mounted on FR4 PCB, mounting pad for drain 6.5 cm ²	-	120	-	K/W

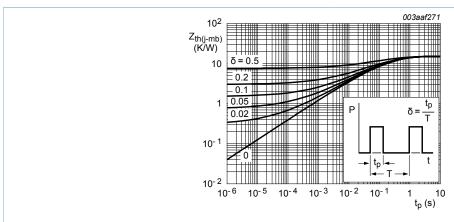


Fig. 5. Transient thermal impedance from junction to solder point as a function of pulse duration

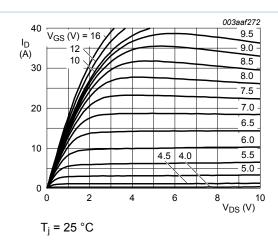
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10. Characteristics

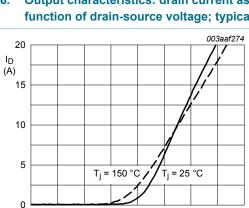
Table 7 Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	55	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 ^{\circ}\text{C}$	50	-	-	V
V _{GS(th)}	gate-source threshold	I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 150 °C	1.2	-	-	V
	voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C	2	3	4	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C}$	-	-	4.4	V
I _{DSS} dra	drain leakage current	V _{DS} = 55 V; V _{GS} = 0 V; T _j = 25 °C	-	0.05	10	μA
		V _{DS} = 55 V; V _{GS} = 0 V; T _j = 150 °C	-	-	100	μA
I _{GSS}	gate leakage current	V _{GS} = 10 V; V _{DS} = 0 V; T _j = 25 °C	-	0.04	1	μA
		V _{GS} = -10 V; V _{DS} = 0 V; T _j = 25 °C	-	0.04	1	μA
		V _{GS} = 10 V; V _{DS} = 0 V; T _j = 150 °C	-	-	10	μA
		V _{GS} = -10 V; V _{DS} = 0 V; T _j = 150 °C	-	-	10	μA
Doon	drain-source on-state	V _{GS} = 10 V; I _D = 5 A; T _j = 150 °C	-	-	148	mΩ
	resistance	V _{GS} = 10 V; I _D = 5 A; T _j = 25 °C	-	65	80	mΩ
V _{(BR)GSS}	gate-source	V _{DS} = 0 V; T _j = 25 °C; I _G = 1 mA	16	-	-	V
	breakdown voltage	V _{DS} = 0 V; T _j = 25 °C; I _G = -1 mA	16	-	-	V
Dynamic	characteristics					
C _{iss}	input capacitance	V _{GS} = 0 V; V _{DS} = 25 V; f = 1 MHz;	-	365	500	pF
Coss	output capacitance	T _j = 25 °C	-	110	135	pF
C _{rss}	reverse transfer capacitance		-	60	85	pF
t _{d(on)}	turn-on delay time	V_{DS} = 30 V; R_L = 4.3 Ω ; V_{GS} = 10 V;	-	9	14	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_{mb} = 25 ^{\circ}C; I_{D} = 7 A$	-	15	25	ns
t _{d(off)}	turn-off delay time		-	18	27	ns
t _f	fall time		-	12	18	ns
g _{fs}	transfer conductance	V_{DS} = 25 V; I_{D} = 5 A; T_{j} = 25 °C	1	4	-	S
Source-d	rain diode			1	1	
V _{SD}	source-drain voltage	$I_S = 5 \text{ A}; V_{GS} = 0 \text{ V}; T_j \ge -55 \text{ °C};$ $T_j \le 175 \text{ °C}$	-	0.85	1.1	V
t _{rr}	reverse recovery time	$I_S = 5 \text{ A}; dI_S/dt = -100 \text{ A/}\mu\text{s};$	-	38	-	ns
Q _r	recovered charge	V_{GS} = -10 V; V_{DS} = 30 V; $T_j \ge$ -55 °C; $T_j \le$ 175 °C	-	0.2	-	μC

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Output characteristics: drain current as a function of drain-source voltage; typical values



 $V_{DS} > I_D \times R_{DSon}$

Transfer characteristics: drain current as a Fig. 8. function of gate-source voltage; typical values

V_{GS} (V)

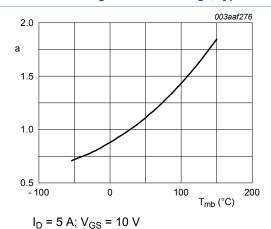


Fig. 10. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

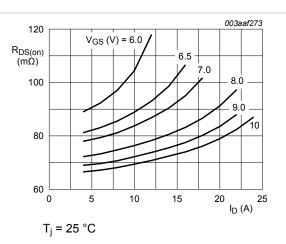
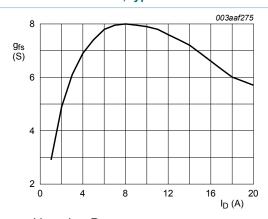
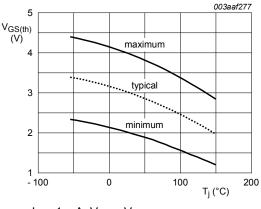


Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



 $V_{DS} > I_D \times R_{DSon}$

Fig. 9. Forward transconductance as a function of drain current; typical values



 $I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig. 11. Gate-source threshold voltage as a function of junction temperature

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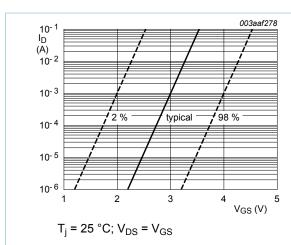


Fig. 12. Sub-threshold drain current as a function of gate-source voltage

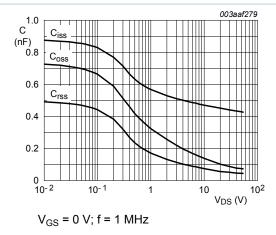


Fig. 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

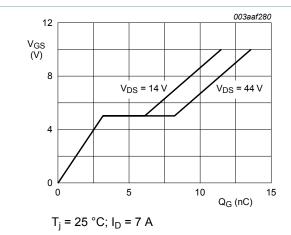


Fig. 14. Gate-source voltage as a function of gate charge; typical values

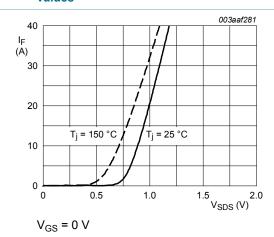
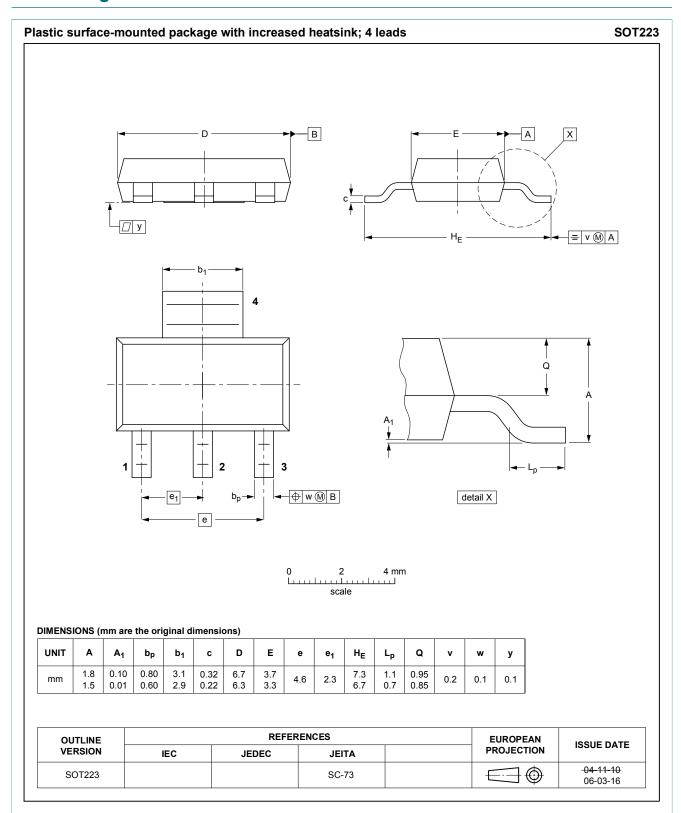


Fig. 15. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

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11. Package outline



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12. Legal information

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Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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